

ARFTG-NIST Short Course on Microwave Measurements, Winter 2020 - Draft Agenda

Microwave Fundamentals

Modern Network Analyzer Calibration Techniques

Rusty Myers – Keysight Technologies

Microwave Power and Traceability

Aaron Hagerstrom – NIST

On-Wafer Materials Measurements

James C. Booth – NIST

High-Speed Oscilloscopes, What the Manual Doesn't Tell You

Paul D. Hale - NIST

On-Wafer Measurements and Microwave Integrated Circuits

Fundamentals of On-Wafer Measurements

Dylan Williams – NIST

Traceable On-Wafer Measurements at mm-Wave Frequencies

Uwe Arz - Physikalisch-Technische Bundesanstalt (PTB)

Non-Contact Wafer Probing

Kubilay Sertel - TeraProbes, Inc.

On-Wafer System Calibration for mm-Wave Frequency Applications

Andrej Rumiantsev - MPI Corporation, and Marco Spirito – Delft University of Technology

Software Tools and Modeling

Multi-Physics Measurements and Modeling

Peter Aaen – Colorado School of Mines

Software for Vector Signal Analysis

Raj Sodhi – Keysight Technologies

Everything You Can Do With Vector Nonlinear Microwave Measurements

Patrick Roblin – The Ohio State University

Introduction to X-Parameters

Jan Verspecht - Keysight Technologies